	•	
	SDLS046	POSITI
•	Operation from Very Slow Edges	SN5413, S

- Improved Line-Receiving Characteristics
- High Noise Immunity

description

Each circuit functions as a 4-input NAND gate, but because of the Schmitt action, it has different input threshold levels for positive (V_{T+}) and for negative going (V_{T-}) signals.

These circuits are temperature-compensated and can be triggered from the slowest of input ramps and still give clean, jitter-free output signals.

The SN5413 and SN54LS13 are characterized for operation over the full military temperature range of ~55°C to 125°C. The SN7413 and SN74LS13 are characterized for operation from 0°C to 70°C.

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-13.

Pin numbers shown are for D, J, N, and W packages.

SN5413, SN54LS13, SN7413, SN74LS13 DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGERS

DECEMBER 1983-REVISED MARCH 1988



NC-No internal connection

logic diagram (positive logic)



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SN5413, SN54LS13, SN7413, SN74LS13 DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGERS

schematics



NOTE 1: Voltage values are with respect to network ground terminal.



SN5413, SN7413 DUAL 4-INPUT **POSITIVE-NAND SCHMITT TRIGGERS**

recommended operating conditions

		SN5413	3	SN7413			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
VCC Supply voltage	4.5	5	5,5	4,75	5	5.25	V
IOH High-level output current			- 0.8			- 0.8	mA
IOL Low-level output current			16		-	16	mA
TA Operating free-air temperature	- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDI	TONS [†] MI	N TYP	MAX	UNIT
V _{T+}	V _{CC} = 5 V	1	5 1.7	2	V
V _{T-}	V _{CC} = 5 V	0	6 0.9	1.1	
Hysteresis (V _{T+} –V _T)	V _{CC} = 5 V	0	4 0.8		V
Vik	V _{CC} = MIN, I ₁ = -12 mA			- 1.5	V
∨он	V _{CC} = MIN, V _I = 0.6 V, I _{OH} = - 0	.8 mA 2	4 3,4		V
VOL	V _{CC} = MIN, V ₁ = 2 V, I _{OL} = 16	nA	0.2	0,4	V
	V _{CC} = 5 V, V ₁ = V _{T+}		- 0.65		mΑ
T-	$V_{CC} = 5 V$, $V_{I} = V_{T-}$		- 0.85	i	mA
4	V _{CC} = MAX, V _I = 5.5 V			1	mA
Чн	VCC = MAX. VIH = 2.4 V			40	μA
비니	V _{CC} = MAX, V _{IL} = 0.4 V		t –	- 1.6	mA
I _{OS} §	V _{CC} = MAX,	- 1	8	- 55	mΑ
ГССН	V _{CC} = MAX		14	23	mA
^I CCL	V _{CC} = MAX		20	32	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. [‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$. § Not more than one output should be shorted at a time.

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switching characteristics, VCC = 5 V, TA = 25° C

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN	түр	MAX	UNIT	
tPLH	Any	Y	R ₁ = 400 Ω,	C ₁ = 15 pF		18	27	ns
tPHL						15	22	ns



SN54LS13, SN74LS13 **DUAL 4-INPUT** POSITIVE-NAND SCHMITT TRIGGERS

recommended operating conditions

	S	SN54LS13			SN74L\$13		
	MIN	NOM	MAX	MIN	NOM	MAX	TINU
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
OH High-level output current			- 0.4			0,4	mA
OL Low-level output current			4			8	mA
TA Operating free-air temperature	- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS			5	SN54LS	13					
PARAMETER		TEST CON	DITIONS.		MIN	TYP‡	MAX	MIN	түр‡	MAX	
VT+	V _{CC} = 5 V				1.4	1,6	1.9	1.4	1.6	1.9	v
V _T	V _{CC} = 5 V				0,5	0,8	1	0.5	0.8	1	V
Hysteresis (V _{T+} -V _T _)	V _{CC} = 5 V				0.4	0.8		0.4	0.8		v
Vik	V _{CC} = MIN,	l _l = - 18 mA					- 1.5			- 1.5	V
∨он	V _{CC} = MIN,	V1 = 0.5 V,	l _{OH} ≑ – 0,4 m	A	2.5	3.4		2.7	3.4		V
				l _{OL} ≈ 4 mA		0.25	0.4		0.25	0.4	
VOL	V _{CC} = MIN,	V ₁ = 1.9 V		IOL = 8 mA					0.35	0.5	V V
۶L+	V _{CC} = 5 V,	$v_1 = v_{T+}$				- 0.14			- 0.14		mA
IT	V _{CC} = 5 V,	$v_1 = v_{T-1}$				- 0,18			- 0.18		mA
I	V _{CC} = MAX,	V = 7 V					0,1			0.1	mΑ
Чн	V _{CC} = MAX,	V _{IH} = 2.7 V					20			20	µА
۱ _۱ ۲	V _{CC} = MAX,	V _{1L} = 0.4 V					- 0.4			- 0.4	mΑ
los§	V _{CC} = MAX				- 20		- 100	- 20		- 1 0 0	mΑ
1ссн	V _{CC} = MAX					2,9	6		2,9	6	mΑ
ICCL	VCC = MAX					4.1	7		4.1	7	mА

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$. § Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V , T_A = 25 $^{\circ}$ C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	түр	МАХ	UNIT
tPLH	Any	×	$R_1 = 2 k \Omega_1$	C _L = 15 pF	L	15	22	រាន
TPHL						18	27	ns



SN5413, SN54LS13, SN7413, SN74LS13 DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGERS



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SN5413, SN7413 DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGERS



TYPICAL CHARACTERISTICS OF '13 CIRCUITS





Data for temperatures below 0°C and 70°C and supply voltages below 4.75 V and above 5.25 V are applicable for SN5413 only.



SN54LS13, SN74LS13 DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGERS



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TYPICAL CHARACTERISTICS OF 'LS13 CIRCUITS

Data for temperatures below 0°C and above 70°C and supply voltages below 4.75 V and above 5.25 V are applicable for SN54LS13 only.



SN54LS13, SN74LS13 DUAL 4-INPUT POSITIVE-NAND SCHMITT TRIGGERS



TYPICAL CHARACTERISTICS OF 'LS13 CIRCUITS



Date for temperatures below 0°C and above 70°C and supply voltages below 4.75 V and above 5.25 V are applicable for SN54LS13 only.



SN5413, SN54LS13, SN7413, SN74LS13 **DUAL 4 INPUT POSITIVE-NAND SCHMITT TRIGGERS**



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TYPICAL APPLICATION DATA



PULSE STRETCHER



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